

<b>Notice of References Cited</b>	Application/Control No. 09/881,129	Applicant(s)/Patent Under Reexamination TONOUCHI, TOSHIO	
	Examiner Ajay M Bhatia	Art Unit 2143	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0212599	11-2003	Kepecs, Jonathan	705/14
	B	US-6,584,097	06-2003	Malik, Dale W.	370/352
	C	US-6,507,870	01-2003	Yokell et al.	709/225
	D	US-5,948,040	09-1999	DeLorme et al.	701/201
	E	US-5,877,704	03-1999	Yoshida, Ichiro	340/932.2
	F	US-5,832,457	11-1998	O'Brien et al.	705/14
	G	US-5,832,451	11-1998	Flake et al.	705/5
	H	US-6,584,097	06-2003	Malik, Dale W.	370/352
	I	US-6,690,929	02-2004	Yeh, Hsi-Jen James	455/406
	J	US-6,538,416	03-2003	Hahne et al.	370/431
	K	US-2002/0042738	04-2002	Srinivasan et al.	705/14
	L	US-2003/0216172	11-2003	LeMay et al.	463/29
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2002015191 A	01-2002	Japan	MIZOGUCHI, YOSUKE	G06F 17/60
	O	WO 200063808 A1	10-2000	World Intellect	BARNETT et al.	G06F 17/60
	P	JP 10027036 A	01-1998	Japan	USUI, TATSUO	G06F 01/00
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.